

IDC08S60CE

2nd generation thinQ![™] SiC Schottky Diode

Applications:

- Revolutionary semiconductor material -Silicon Carbide
- Switching behavior benchmark
- No reverse recovery

Features:

- No temperature influence on the switching behavior
- No forward recovery
- WHigh surge current capability

• SMPS, PFC, snubber



Chip Type	V_{BR}	I _F	Die Size	Package
IDC08S60CE	600V	8A	1.658 x 1.52 mm ²	sawn on foil

Mechanical Parameter					
Raster size	1.658x 1.52				
Anode pad size	1.421 x 1.283	mm²			
Area total	2.52				
Thickness	355	μm			
Wafer size	100	mm			
Max. possible chips per wafer	2682				
Passivation frontside	Photoimide				
Anode metal	3200 nm Al				
Cathode metal	Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	Electrically conductive glue or solder				
Wire bond	AI, ≤ 350μm				
Reject ink dot size	Ø ≥ 0.3 mm				
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°0				



IDC08S60CE

Maximum Ratings

Parameter	Symbol	Condition	Value	Unit
Repetitive peak reverse voltage	V_{RRM}	T _{vj} = 25 °C	600	V
DC blocking voltage	V _{DC}		600]
Continuous forward current limited by T_{vjmax}	I _F	T _{vj} < 150°C	8	
Surge non repetitive forward current sine halfwave	I _{F,SM}	$T_{\rm C}$ =25°C, $t_{\rm P}$ =10 ms	59	A
Repetitive peak forward current limited by T_{vjmax}	I _{F,RM}	$T_{\rm C} = 100^{\circ} {\rm C}, T_{\rm vj} = 150^{\circ} {\rm C},$ D = 0.1	35	
Non-repetitive peak forward current	$I_{F,max}$	$T_{\rm C}$ =25°C, $t_{\rm p}$ =10 μ s	264	
Operating junction and storage temperature	$T_{\rm vj}$, $T_{\rm stg}$		-55+175	°C

Static Characteristics (tested on wafer)

Parameter	Symbol	Condi	Value			Unit	
- raiailletei	Syllibol	Condi	tions	min.	Тур.	max.	Ullit
Reverse current	I_{R}	V _R =600V	<i>T</i> _{vj} =25°C		1	100	μΑ
Diode forward voltage	V _F	I _F =8A	T _{vj} =25°C		1.5	1.7	V

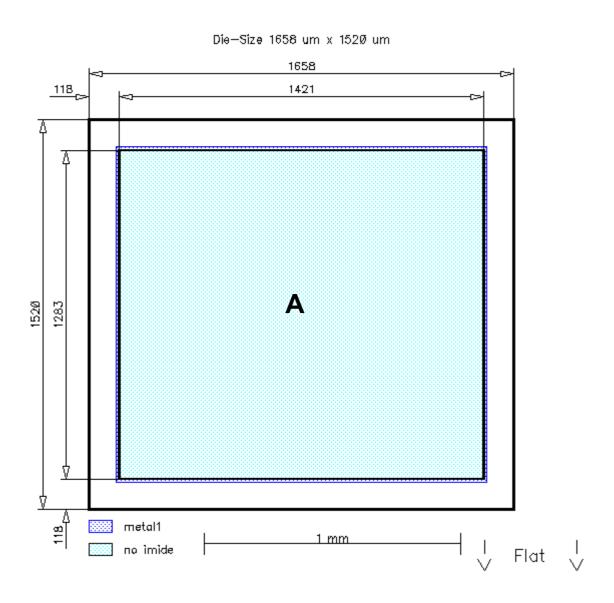
Dynamic Characteristics, at T_{vi} = 25 °C, unless otherwise specified, tested at component

Devenuetes	Symbol	Conditions		Value			I I mit
Parameter	Symbol			min.	Тур.	max.	Unit
Total capacitive charge	Q _C	$I_F <= I_{F,max}$ - $di/dt = 200 A/\mu s$ $V_R = 400 V$	T _{vj} = 150 °C		19		nC
Switching time 1)	t _c		T _{vj} = 150 °C			<10	ns
Total capacitance	С	f=1MHz	V _R =1V		310		
			V _R =300V		50		pF
			V _R =600V		50		

 $^{^{1)}}$ $t_{\rm c}$ is the time constant for the capacitive displacement current waveform (independent from $T_{\rm vj}$, $I_{\rm LOAD}$ and di/dt), different from $t_{\rm rr}$ which is dependent on $T_{\rm vj}$, $I_{\rm LOAD}$ and di/dt. No reverse recovery time constant $t_{\rm rr}$ due to absence of minority carrier injection



Chip drawing



A: Anode pad



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Description

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

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